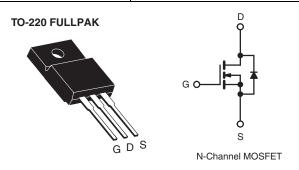


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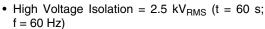
Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	450			
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V	0.63		
Q _g (Max.) (nC)	80			
Q _{gs} (nC)	12			
Q _{gd} (nC)	41			
Configuration	Single			



FEATURES

· Isolated Package





RoHS*

- Sink to Lead Creepage Dist. = 4.8 mm
- · Dynamic dV/dt Rating
- Low Thermal Resistance
- · Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 FULLPAK eliminates the need for additional insulating hardware in commercial-industrial applications. The molding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The FULLPAK is mounted to a heatsink using a single clip or by a single screw fixing.

ORDERING INFORMATION	
Package	TO-220 FULLPAK
Lead (Pb)-free	IRFI744GPbF
	SiHFI744G-E3
SnPb	IRFI744G
	SiHFI744G

PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V_{DS}	450	V	
Gate-Source Voltage	V_{GS}	± 20] v		
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 ^{\circ}C$	1-	4.9		
	$T_C = 100 ^{\circ}C$	ID	3.1	Α	
Pulsed Drain Current ^a	I _{DM}	20			
Linear Derating Factor		0.32	W/°C		
Single Pulse Avalanche Energy ^b	E _{AS}	130	mJ		
Repetitive Avalanche Current ^a	I _{AR}	4.9	Α		
Repetitive Avalanche Energy ^a	E _{AR}	4.0	mJ		
Maximum Power Dissipation	T _C = 25 °C	P_{D}	40	W	
Peak Diode Recovery dV/dtc	dV/dt	3.5	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s	-	300 ^d		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	6-32 OF IVIS SCIEW		1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 9.6 mH, R_G = 25 Ω , I_{AS} = 4.9 A (see fig. 12).
- c. $I_{SD} \le 8.8$ A, $dI/dt \le 200$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFI744G, SiHFI744G

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THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	3.1	C/VV

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	450	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.59	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zana Oata Wallana Busin Oamani		V _{DS} =	V _{DS} = 450 V, V _{GS} = 0 V		-	25	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 360 \	/, V _{GS} = 0 V, T _J = 125 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.9 A ^b	-	-	0.63	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	V _{DS} = 50 V, I _D = 2.9 A ^b		-	-	S
Dynamic							
Input Capacitance	C _{iss}	$V_{GS} = 0 V$,		-	1400	-	_
Output Capacitance	C _{oss}	1	$V_{DS} = 25 V$,		370	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5 f = 1 MHz		-	140	-	pF
Drain to Sink Capacitance	С			-	12	-	1
Total Gate Charge	Qg			-	-	80	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 8.8 \text{ A}, V_{DS} = 360 \text{ V},$ see fig. 6 and 13^b	-	-	12	
Gate-Drain Charge	Q _{gd}	1	occ ng. c and re	-	-	41	
Turn-On Delay Time	t _{d(on)}			-	8.7	-	
Rise Time	t _r	V_{DD} = 225 V, I_{D} = 8.8 A, R_{G} = 9.1 Ω , R_{D} = 25 Ω , see fig. 10 ^b		-	28	-	- ns
Turn-Off Delay Time	t _{d(off)}			-	58	-	
Fall Time	t _f			-	27	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s				l.		
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4.9	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	20	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 8.8 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		_	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 8.8 A, dl/dt = 100 A/μs ^b		-	490	740	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.2	4.8	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is d			ninated by	y L _S and I	_D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300~\mu s;$ duty cycle $\leq 2~\%.$



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

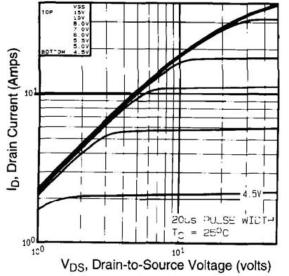


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

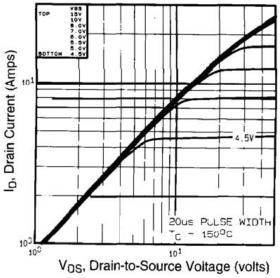


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

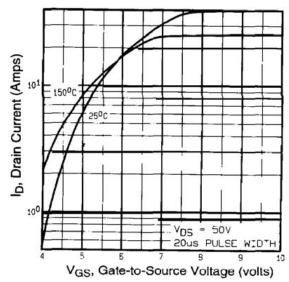


Fig. 3 - Typical Transfer Characteristics

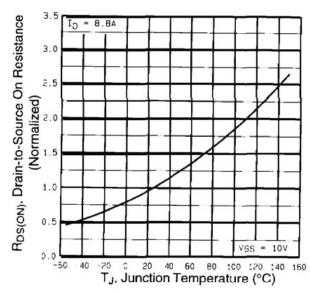


Fig. 4 - Normalized On-Resistance vs. Temperature

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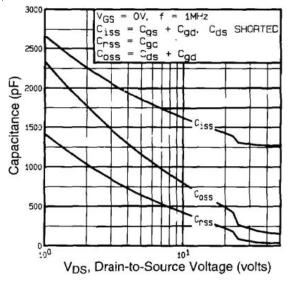


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

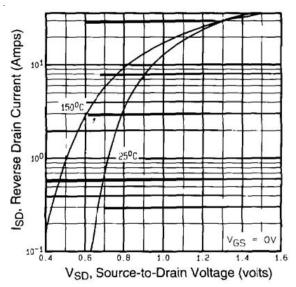


Fig. 7 - Typical Source-Drain Diode Forward Voltage

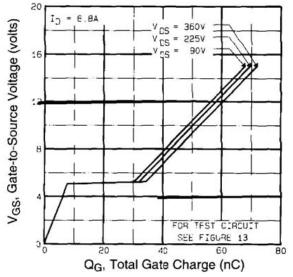
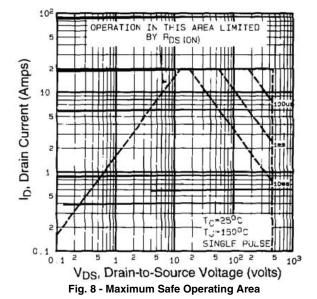
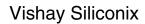


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage







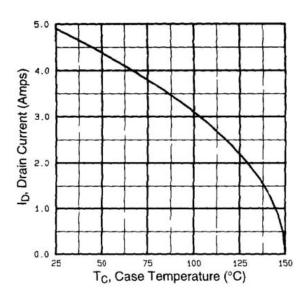


Fig. 9 - Maximum Drain Current vs. Case Temperature

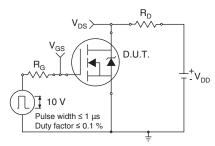


Fig. 10a - Switching Time Test Circuit

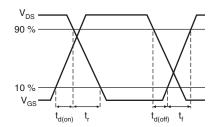


Fig. 10b - Switching Time Waveforms

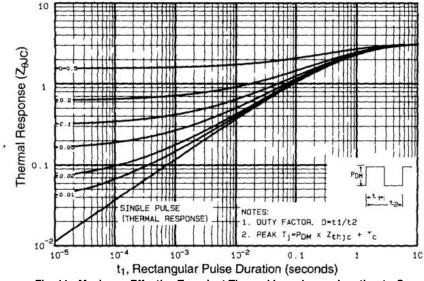


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

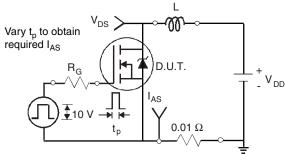


Fig. 12a - Unclamped Inductive Test Circuit

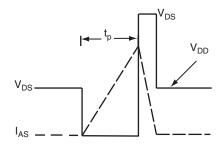


Fig. 12b - Unclamped Inductive Waveforms

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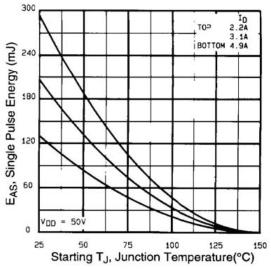


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

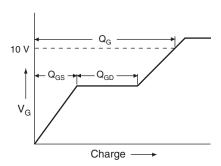


Fig. 13a - Basic Gate Charge Waveform

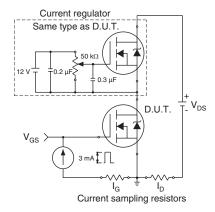
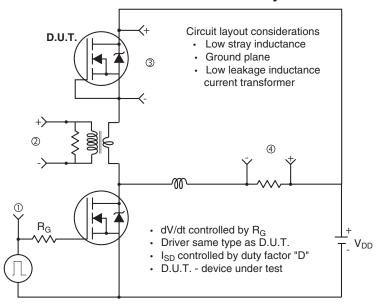
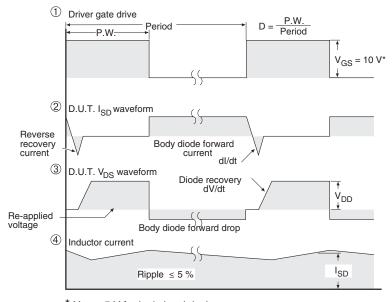


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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